JUN 8 2007

## TED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shiro Fujieda

Attorney Docket No.: OMRNP008

Application No.: 09/974,539

Examiner: B.Q. Le

Filed: October 9, 2001

Group: 2624

Title: CONTOUR INSPECTION METHOD AND **APPARATUS** 

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents. Alexandria, Virginia 22313-1450 on June 5, 2007.

CERTIFICATE OF MAILING

Signed:

Deborah Neill

## INFORMATION DISCLOSURE STATEMENT 37 CFR §§1.56 AND 1.97(b)

Commissioner for Patents Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

The cited reference was considered pertinent to the present application for disclosing a method of detecting a defect by calculating the directions of edge pixels on a target gradation image for detection and obtaining angular differences between edge pixels.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

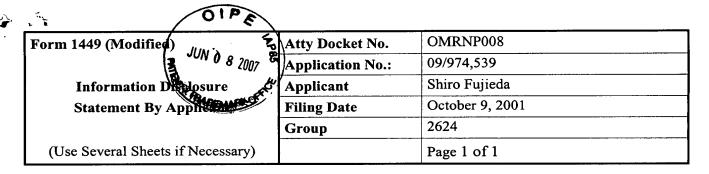
This Information Disclosure Statement is believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. OMRNP008).

Respectfully submitted,

BEYER WEAVER LLP

Régistration No. 29,093

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#### **U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
	A.						
	В.						
	C.						
	D.						

# Foreign Patent or Published Foreign Patent Application

Examiner		Document No.	Publication	Country or	Class	Sub-	<b>Translation</b>	
Initial			Date	Patent Office		Class	Yes	No
	E.	61-150080	07/08/86	Japan			X	

### **Other Documents**

Examiner Initial	No.	Author, Title, Place (e.g. Journal) of Publication, Date
	F.	Japan patent application No. 2001-323906, Office Action dated
		January 7, 2004.
	G.	
	H.	
	I.	
	J.	
	K.	
	L.	·
	M.	
	N.	
	O.	
	P.	
	Q.	
	R.	

Examiner	Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.